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Optical and Electrical Properties of Copper Telluride Thin Films

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Abstract: Copper Telluride (CuTe) thin films have been successfully deposited on a glass substrate Fluorine Tin oxide (FTO) by electrodeposition technique. The absorbance was measured using M501 UV-visible spectrophotometer in the wavelength range of 200-900nm. Copper Telluride (CuTe) thin films were investigated at room temperature. Optical absorption study showed that CuTe films were of indirect band gap type semiconductor with band gap energy of 2.4-2.8eV.

Keywords: Thin Film, Fluorine Tin oxide (FTO), Electrodeposition, Optical and Electrical properties.

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Introduction

Copper Telluride have attracted much interest because of their potential applications in thermoelectric devices and in herterojunction structures ^[1]. Thin film solar cells using copper telluride (CuTe) absorber layers are one of the primary contenders for large-scale commercialization of photovoltaic. Numerous applications based on CuTe have been deployed worldwide such as in radiation detectors, electro-optical modulators and solar cell fabrication ^[2]. Currently, many techniques are used and have been reported to grow the CuTe thin films such as vacuum evaporation, sputtering, electrodeposition, metal vapor organic deposition, closed spaced sublimation and spray pyrolysis. Among these techniques, electrodeposition technique has become an attractive and potential technique due to its many advantages: low cost photocell fabrication, easily adapted from the laboratory to industrial scale, no wastage of materials, short deposition time, simple process and higher deposition rate ^[3]. CuTe nanocrystal films onto dielectric polymer thin film ^[4] and quantum dot sensitized solar cells with improved efficiency ^[5] have been prepared by using electrodeposition technique.

The coating can be made in any shape and the film thickness can be controlled by the deposition conditions ^[6]. Copper Telluride thin films have a number of applications in various devices such as solar

cells, super ionic conductors, photo-detectors, photothermal conversion, electroconductive electrodes, and microwave shield coating ^[7].

An optical characteristic of metallic nanowires is the one of the emerging area of application of nanotechnology, ultrahigh density magnetic recording, ultrafast optical switching, and microwave devices. Copper telluride belongs to the copper chalcogenide (group's II-VI compound) group of materials. Controlled hydrothermal synthesis and growth mechanism of various nanostructured films of copper and silver telluride is explained ^[8]. The deposition of metal chalcogenide thin films by successive ionic layer adsorption and a reaction (SILAR) method is reported in ^[9]. The preparation and characterization of copper telluride thin films by the modified chemical bath deposition (M-CBD) method is also reported in ^[10]. The hydrophilic nature of electrodeposited copper telluride and stress, mass, fringe width and thickness of the CuTe thin film is reported in ^[11].

Material and Methods

Copper Telluride thin films were prepared by electrodeposition Technique on the glass substrates Fluorine Tin Oxide (FTO). The substrates were cleaned ultrasonically by detergent solution, acetone, and deionized water, respectively, to ensure the

complete cleanness. The reaction bath for the deposition of Copper Telluride (CuTe) was composed of four electrolyte Telluride IV Oxide (TeO₂), (CuSO₂.5H₂O), Potassium tetraoxosulphate VI (K₂SO₄) and Tetraoxosulphate VI acid (H₂SO₄). The growth of (CuTe) films were determined with respect to the different bath parameters which includes time of deposition and substrate for the deposition. 20cm³ each of TeO₂ and (CuSO₂.5H₂O) was measured into 100cm³ beaker using burette. 5.00cm³ of K₂SO₄ was measured into the same 100cm³ beaker containing TeO₂ and (CuSO₂.5H₂O)

respectively to serve as the inert electrolyte which helps to dissociate the Copper from (CuSO₂.5H₂O) to form the required CuTe film on the substrate and the solution was acidified with 5.00cm³ of dilute H₂SO₄ which serves to adjust the P^H value. The entire mixture was stirred with the glass rod to achieve uniformity. In each of the reaction baths prepared, a glass substrate and platinum electrode were connected to a DC power supply source and the voltage was maintained at 7V for different time intervals.

Table 1: Variation of Parameters CuTe Thin films

Samples	Volume of H ₂ SO ₄ (cm ³)	Volume of K ₂ SO ₄ (cm ³)	Volume of TeO ₂ (cm ³)	Volume of (CuSO ₂ .5H ₂ O) (cm ³)	Voltage (V)	Time (minutes)
CuTe1	5.00	5.00	20.00	20.00	7.00	5.00
CuTe2	5.00	5.00	20.00	20.00	7.00	7.00
CuTe3	5.00	5.00	20.00	20.00	7.00	9.00

The Optical Properties of Copper Telluride Thin Films

In Figure 1, the absorbance of Copper Telluride thin film of sample CuTe1 increase and decreasing with the wavelength while sample CuTe2 and CuTe3 decreases as the wavelength increases. The absorbance generally shows high in the UV region and IR regions. The high absorbance in UV region makes the material useful in formation of p-n junction solar cells with other suitable thin film materials for photovoltaic application. These

optical properties make Copper Telluride thin films nice glazing material for maintaining cool interior in buildings in warm climate regions while still keeping the rooms well illuminated. To ensure that the thermal radiation from the warm glazing to the interior is inhibited and the thermal energy dissipated in the glazing due to absorption is predominantly transferred to the exterior by enhanced convective heat transfer of the glazing to the exterior as reported in [12].

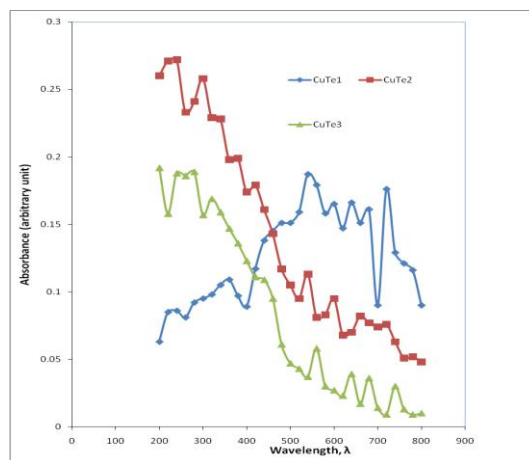


Figure 1: The Plot of Absorbance as a function of Wavelength

In Figure 2 shows the transmittance spectra of the Copper Telluride thin films deposited. The transmittance spectra shows a sinusoidal form of wave motion, which means Copper Telluride increase and decreases with the wavelength, but both films shows a very high transmittance in the VIS-NIR regions of the electromagnetic spectrum which makes the material a

good application in the production of blue and green light emitting device as reported in [13,14].

The optical reflectance of copper Telluride thin films shows that the films shows a sinusoidal form of wave motion; which means Copper Telluride increase and decreases with the wavelength. Both

samples show a high reflectance in UV and IR region of the electromagnetic spectrum.

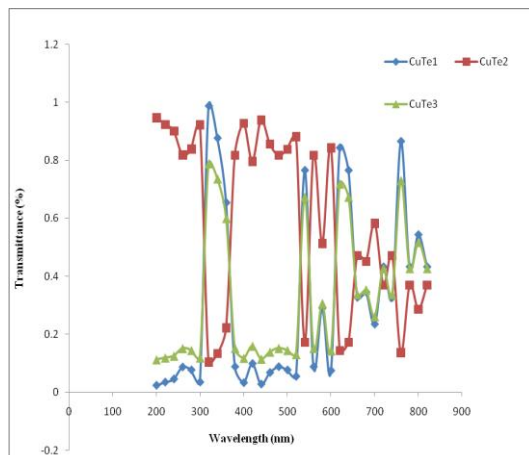
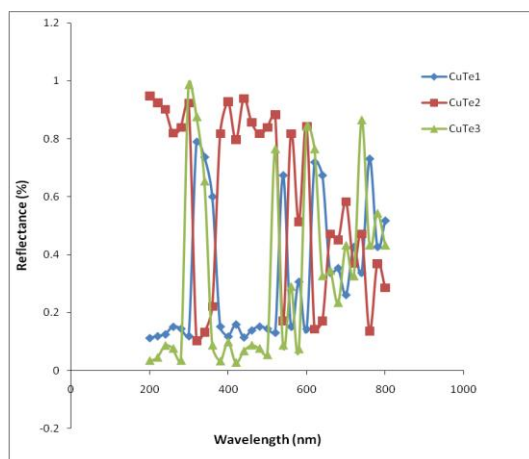


Figure 2: The Plot of Transmittance as a function of Wavelength



The band gap energy and transition types were derived from mathematical processing of the data obtained from the optical absorbance versus photon energy with the following relationships for near edge absorption.

$$\alpha = (h\nu - \epsilon_g) n/2 \quad (1)$$

Where ν is the frequency, h is the Planck's constant, while n carries the value of either 1 or 4. The band gap ϵ_g could be obtained from a straight line plot of α^2 as a function of $h\nu$; an extrapolation of the value of α^2 to zero will give band gap. If a straight line graph is obtained from $n=1$, it indicates a direct transition between the states of the semiconductor, whereas the transition is indirect if a straight line graph is obtained from $n = 4$. The band gap energy of 2.4eV - 2.8eV was obtained with an indirect transition shows in figure 3-4.

Electrical Properties of CuTe Thin films

The electrical properties of the deposited copper selenide films were studied using a standard four point

probe technique. The arrangement was made in such a way that the voltage across the transverse distance of the films was measured using silver paste on top of the coated slide to ensure good ohmic contact to the film. The four point probes were arranged such that the two outer probes were connected to current supply and the two inner probes to a voltage supply. As current flows between the two outer probes, voltage drop across the inner probes was measured. The sheet resistivity of the thin film depends on the current, voltage and thickness values of prepared thin film. Equations:

$$\ell = \frac{\pi V}{\ln 2 I} = 4.523t \quad \dots\dots\dots(2)$$

$$R_s = \frac{\text{resistivity}}{4.523 \times \text{thickness}} = \frac{\ell}{4.523t} \quad \dots\dots\dots(3)$$

$$\sigma = \frac{1}{\ell} \quad \dots\dots\dots(4)$$

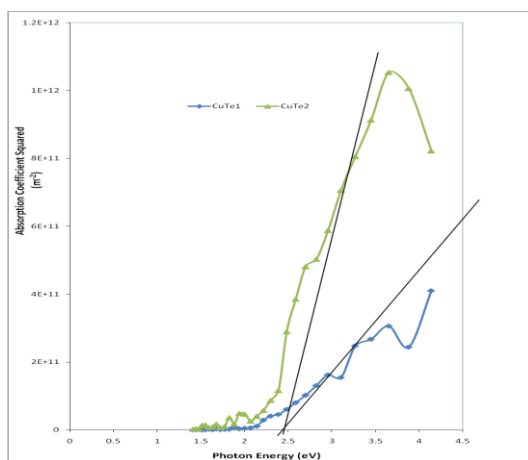


Figure 3: The Plot of Absorption Coefficient Square as a function of photo Energy

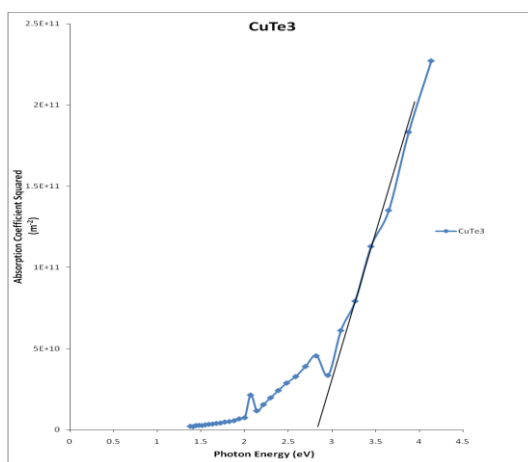


Figure 4: The Plot of Absorption Coefficient Square as a function of photo Energy

Table1: Electrical property of CuTe films

Samples	Thickness, t (nm)	Resistivity, ρ (Ωm) ⁻¹	Conductivity, σ (Ωm) ⁻¹
CuTe1	289	4.85x10 ⁶	6.98x10 ⁵
CuTe2	307	7.95x10 ⁶	8.77x10 ⁵
CuTe3	343	9.78x10 ⁶	9.99x10 ⁵

Table 2 shows the results obtained. The results clearly show that CuTe films have high resistivity and conductivity. As the thickness increases the resistivity and conductivity increased as well which makes the resistivity and conductivity of CuTe suitable for blue, green light and buffer layer in thin film technology. It is a semiconductor that has large potential applications in thin films like photo luminescence and electroluminescent devices as reported in [15,16].

Conclusion

Copper Telluride thin films have been prepared by electrodeposition technique. The

absorbance of Copper Telluride thin film of sample CuTe1 increase and decreasing with the wavelength while sample CuTe2 and CuTe3 decreases as the wavelength increases. The absorbance generally shows high in the UV region and IR regions. The transmittance spectra shows a sinusoidal form of wave motion; which means Copper Telluride increase and decreases with the wavelength, but both films shows a very high transmittance in the VIS-NIR regions of the electromagnetic spectrum which makes the material a good application in the production of blue and green light emitting device. The electrical properties of the films show that the resistivity and conductivity increases as the thickness increases.

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